

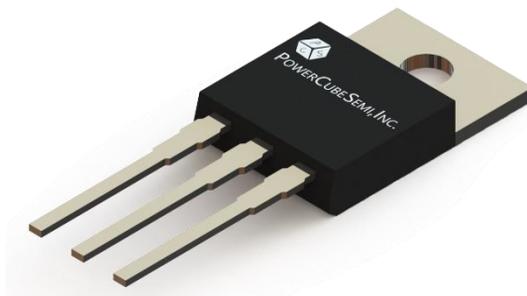
PM005N080AM

80V 120A 5.5mΩ Single N Channel Trench MOSFET with Normal Diode

Features

Si Single N Channel Trench MOSFET

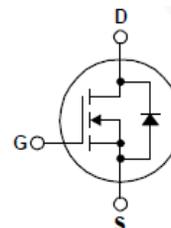
- Rated to 80V at 120Amps @ $T_j = 25^\circ\text{C}$
- Max $R_{DS(on)} = 5.5\text{ m}\Omega$
- Typ $R_{DS(on)} = 4.5\text{ m}\Omega$
- Gate Charge(Typ. $Q_g=61\text{ nC}$)
- 100% UIL Tested
- 100% Rg Tested



PKG type : TO-220

Application

- Low Power Drives
- Light electric vehicles
- DC/DC Converter
- General purpose applications



Description

PM005N080AM, PowerCubeSemi's latest generation of Middle Voltage MOSFET technology, which provides high performance in the lowest RDS(on), fast switching performance, and excellent quality. These devices can also be utilized in industrial applications such as Low Power Drives of E-bike, Light electric vehicles, DC/DC converter, and general purpose applications.

Absolute Maximum Ratings

| Symbol | Parameter | Test Condition | Value | Unit |
|------------|--------------------------------|---------------------------------------------------|------------|------------------|
| BV_{DSS} | Drain-Source Breakdown Voltage | $V_{GS}=0V, I_D=250\mu A$ | 80 | V |
| I_D | Drain Current | $T_c=25^\circ\text{C}$ | 120 | A |
| I_{DM} | Pulsed Drain Current | Pulse width limited by junction temperature | 480 | A |
| V_{GS} | Gate-Source Voltage | | ± 20 | V |
| E_{AS} | Single Pulsed Avalanche Energy | $I_{AS}=19A, V_{GS}=10V$ $V_{DD}=50V, L=1.0mH$ | 181 | mJ |
| P_d | Power Dissipation | $T_c=25^\circ\text{C}$ | 188 | W |
| T_j | Operating Junction Temperature | | 175 | $^\circ\text{C}$ |
| T_{stg} | Storage Temperature | | -55 to 175 | $^\circ\text{C}$ |



Package Marking and Ordering Information

| Device Marking | Device | Package | Packing Method | Tape width | Quantity |
|----------------|-----------|---------|----------------|------------|----------|
| PM005N080AM | PM005N080 | TO-220 | Tube | - | |

Electrical Characteristics of Si MOSFET

| Symbol | Parameter | Test Condition | Numerical | | | Unit |
|--------------|-----------------------------------------|--------------------------------------------------------|-----------|------|-----------|------------|
| | | | Min | Typ. | Max. | |
| BV_{DSS} | Drain-Source Breakdown Voltage | $V_{GS} = 0V, I_D = 250\mu A, T_J = 25^\circ C$ | 80 | - | - | V |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS} = 80V, V_{GS} = 0V$ | - | - | 1 | μA |
| I_{GSS} | Gate-Source Leakage Current | $V_{GS} = \pm 20V, V_{DS} = 0V$ | - | - | ± 100 | nA |
| $V_{GS(th)}$ | Gate Threshold Voltage | $V_{DS} = V_{GS}, I_D = 250\mu A$ | 2.4 | - | 3.8 | V |
| $R_{DS(ON)}$ | Static Drain-Source on state resistance | $V_{GS} = 10V, I_D = 50A$ | - | 4.5 | 5.5 | m Ω |
| g_{FS} | Forward Transconductance | $V_{DS} = 10V, I_D = 50A$ | - | 81 | - | S |
| $t_{d(on)}$ | Turn-on Delay time | $V_{DD} = 40V, I_D = 50A, V_{GS} = 10V, R_G = 3\Omega$ | - | 23.5 | - | ns |
| T_r | Turn-on Rise time | | - | 13.1 | - | |
| $t_{d(off)}$ | Turn-off Delay time | | - | 42.9 | - | |
| T_f | Turn-off Fall time | | - | 13.6 | - | |



Electrical Characteristics of Si MOSFET

| Symbol | Parameter | Test Condition | Numerical | | Unit |
|---------------------|--------------------------------------|-----------------------------------------------------------------------------|-----------|------|-----------------------------|
| | | | Typ. | Max. | |
| $R_{\theta JC}$ | Thermal Resistance, Junction to Case | | 0.8 | - | $^{\circ}\text{C}/\text{W}$ |
| R_g | Gate Resistance | $V_{GS} = 0\text{V}, f = 1.0\text{MHz}$ | 2.5 | - | Ω |
| C_{iss} | Input Capacitance | $V_{DS} = 40\text{V}, V_{GS} = 0\text{V}, f = 1.0\text{MHz}$ | 4137 | - | pF |
| C_{oss} | Output Capacitance | | 969 | - | |
| C_{rss} | Reverse Transfer Capacitance | | 40 | - | |
| $Q_{g(\text{tot})}$ | Total Gate Charge at 10V | $V_{DD} = 40\text{V}, I_D = 50\text{A}$ $V_{GS(\text{on})} = 10\text{V}$ | 61 | - | nC |
| Q_{gs} | Gate to Source Gate Charge | | 18 | - | |
| Q_{gd} | Gate to Drain "Miller" Charge | | 15 | - | |

Electrical Characteristics of Si Diode

| Symbol | Parameter | Test Condition | Numerical | | Unit |
|----------|----------------------------------------------------------|-------------------------------------------------------|-----------|------|------|
| | | | Typ. | Max. | |
| I_S | Maximum Continuous Drain to Source Diode Forward Current | | - | 120 | A |
| I_{SM} | Maximum Pulsed Drain to Source Diode Forward Current | | - | 480 | A |
| V_{SD} | Drain to Source Diode Forward Voltage | $I_S = 50\text{A}, V_{GS} = 0\text{V}$ | 0.9 | 1.2 | V |
| T_{rr} | Reverse Recovery Time | $I_F = 50\text{A}, di_F/dt = 100\text{A}/\mu\text{s}$ | 86 | - | ns |
| Q_{rr} | Reverse Recovery Charge | | 270 | - | nC |

Typical Characteristics

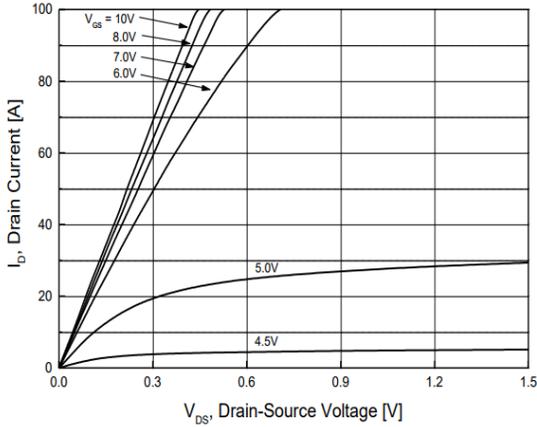


Figure 1. On-Region Characteristics

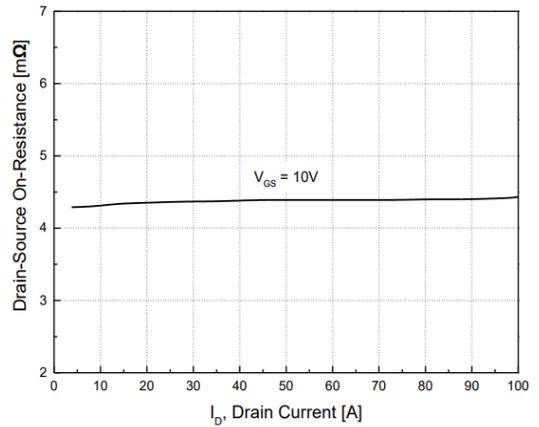


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage

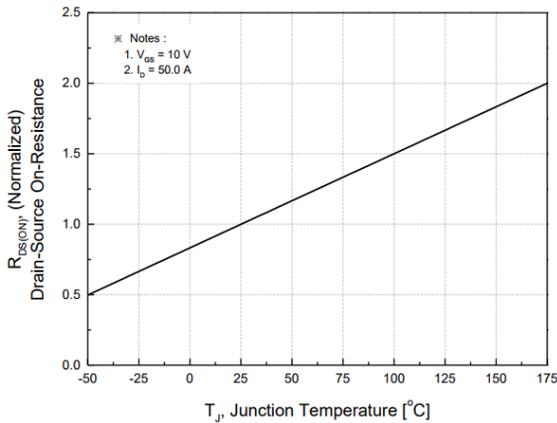


Figure 3. On Resistance Variation with Temperature

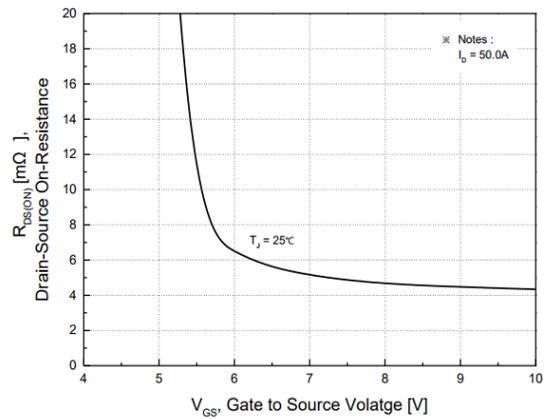


Figure 4. On-Resistance Variation with Gate to Source Voltage

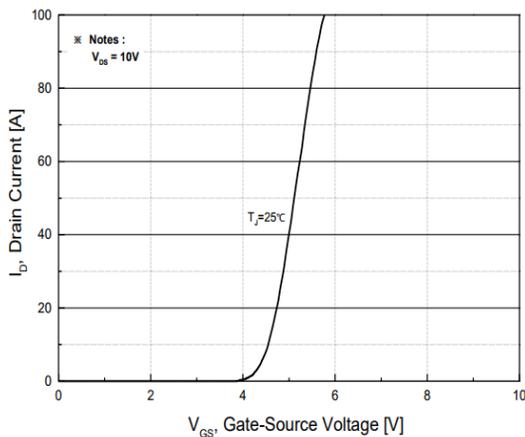


Figure 5. Transfer Characteristics

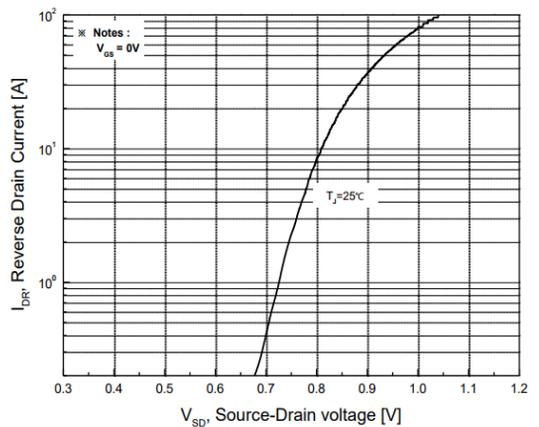


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature

Typical Characteristics

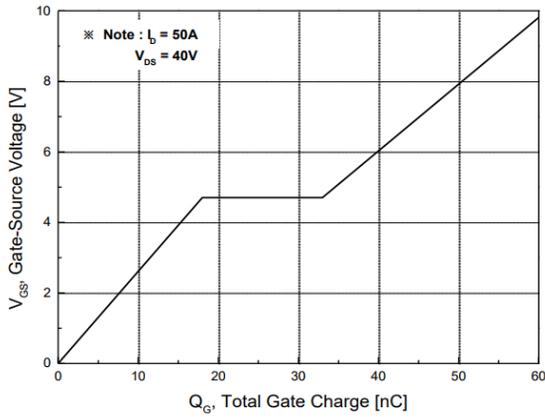


Figure 7. Gate Charge Characteristics

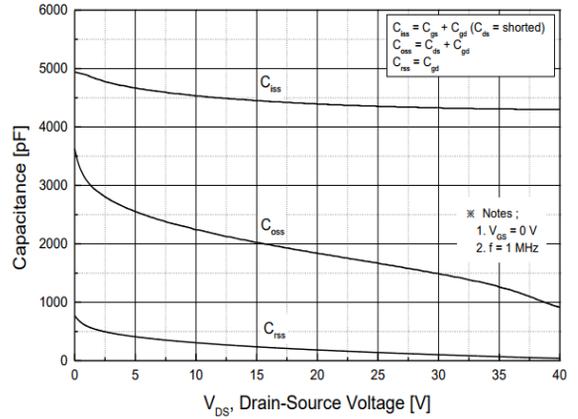


Figure 8. Capacitance Characteristics

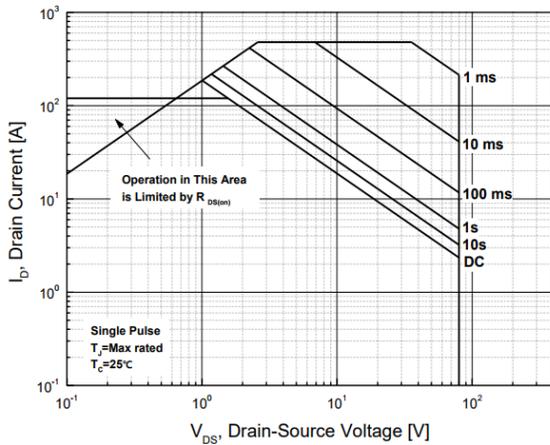


Figure 9. Maximum Safe Operating Area

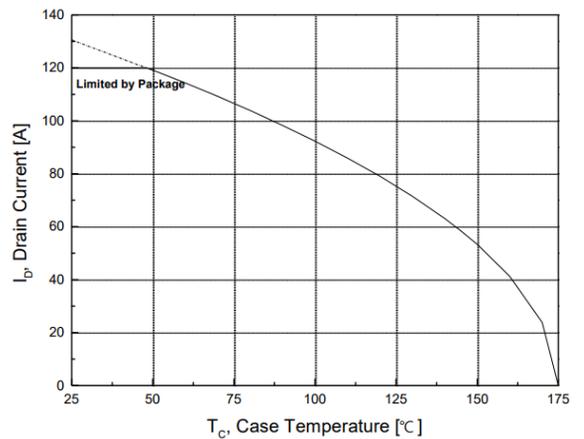


Figure 10. Maximum Drain Current vs. Case Temperature

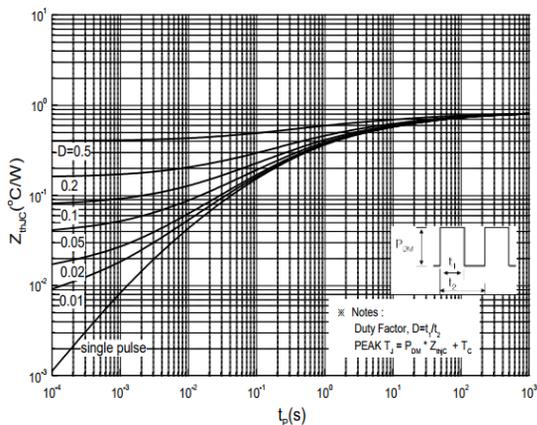


Figure 11. Transient Thermal Response Curve



Package Outline

Unit : mm

